

Notice of References Cited	Application/Control No. 09/917,661	Applicant(s)/Patent Under Reexamination PARVATHALA ET AL.	
	Examiner John J. Tabone, Jr.	Art Unit 2133	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Shen et al., Native Mode Functional Test Generation for Processors with Applications to Self Test and Design Validation, Test Conference, 1998. Proceedings. International, 18-23 Oct 1998, Page(s): 990-999 □□
	V	Chen et al., Software-Based Self-Testing Methodology for Processor Cores, March 2001, Volume: 20 , Issue: 3, On page(s): 369 - 380
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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